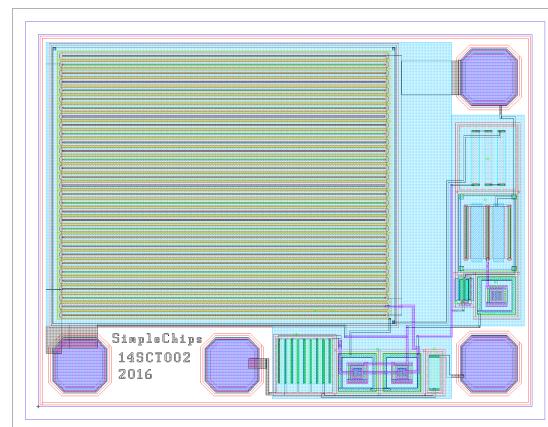


# 14SCT001 OPTO-COUPLER or SSR LED DRIVER

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- Metal Shield to prevent LED interaction.
- Nominal Current 14mA
- Resistor programmable current
- -55C to +125C operation
- Small die size at 1050um X 815um
- Breakdown voltage > 50V
- OFF leakage < +/-100uA

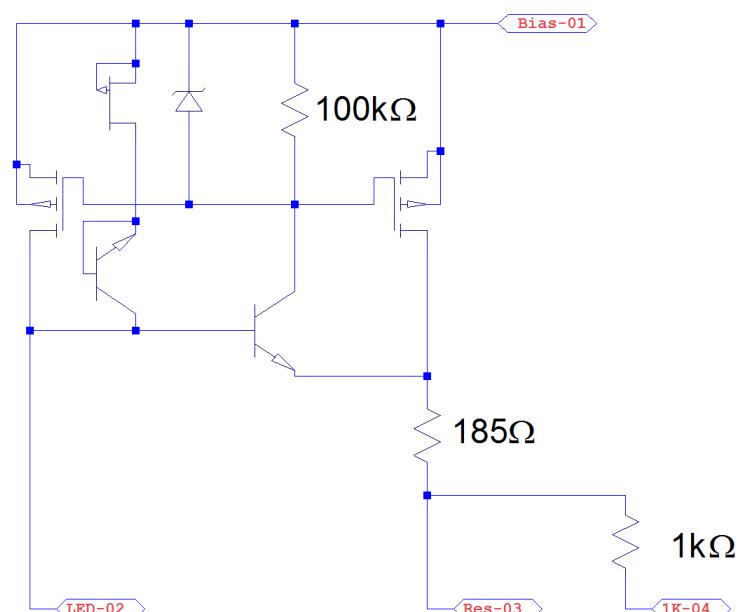
DIE  
(TOP VIEW)



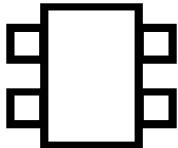
## Description

This device is a resistor programmable current limiter for use in opto-coupler or solid-state relays where a premium is placed on product quality and performance. Nominally set for 14mA using industry standard 2kΩ resistor setting resistor the 14SCT002 delivers steady performance across the entire extended temperature range of -55C to 125C.

## Equivalent circuit:



## Absolute maximum rating



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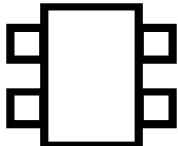
Input Voltage ( $V_{HV} - V_{SS}$ ) . . . . .	.....	.....	.....	+/-50 V
Operating temperature . . . . .	.....	.....	.....	-55 C to 125 C
Storage temperature . . . . .	.....	.....	.....	-65 C to 150 C

## Electrical characteristics at room temperature (25C +/- 2C) (100% tested)

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$ID_{LV2}$ Low Voltage LED Current	$V_{Bias}=4.0V; V_R=2.60V; R=2.0k$	12.1	14.0	15.9	mA
$ID_{HV2}$ High Voltage LED Current	$V_{Bias}=-32.0V; V_R=2.60V; R=2.0k$	12.0	13.8	15.7	mA
$ID_{LV8}$ Low Voltage LED Current 2	$V_{Bias}=6.0V; V_R=2.70V; R=0.80k$	30.0	35.4	42.0	mA
$I_{LV2.0}$ Low Voltage Bias Current	$V_{Bias}=4.0V; V_R=2.60V; R=2.0k$	13.0	15.0	17.0	mA
$I_{HV2.0}$ High Voltage Bias Current	$V_{Bias}=-32.0V; V_R=2.60V; R=2.0k$	12.8	14.8	16.8	mA
$I_{LV0.8}$ Low Voltage Bias Current 2	$V_{Bias}=6.0V; V_R=2.70V; R=0.80k$	32.0	38.0	45.0	mA
$R_{Set}$ Set Resistor	$V=1.0V$	0.75	1.10	1.35	kΩ
$I_{R32}$ Leakage Current at -32V	$V_{Bias}=-32.0V; V_R=0.00V; R=0.0k$	-100	-1.0	0	nA
$I_{T+50}$ Leakage Current at +50V	$V_{Bias}=50.0V; V_R=0.00V; R=0.0k$	10	31.0	100	μA
$I_{T-50}$ Leakage Current at -50V	$V_{Bias}=-50.0V; V_R=0.00V; R=0.0k$	-100	-1.3	0	nA
$I_{S3.8}$ Start-up Current at 3.8V	$V_{Bias}=3.8V; V_R=0.00V; R=0.0k$	5.0	18	100	μA
$I_{S32}$ Start-up Current at 32V	$V_{Bias}=-32.0V; V_R=0.00V; R=0.0k$	10	27.0	100	μA

## Electrical characteristics at COLD temperature (-55C +/- 2C) (Sample tested)

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$ID_{CLV2}$ Low Voltage LED Current	$V_{Bias}=4.0V; V_R=2.25V; R=2.0k$	12.5	14.4	16.2	mA
$ID_{CHV2}$ High Voltage LED Current	$V_{Bias}=-32.0V; V_R=2.25V; R=2.0k$	12.2	14.3	16.1	mA
$ID_{CLV8}$ Low Voltage LED Current 2	$V_{Bias}=6.0V; V_R=2.45V; R=0.80k$	30.0	37.3	42.0	mA
$I_{CLV2.0}$ Low Voltage Bias Current	$V_{Bias}=4.0V; V_R=2.25V; R=2.0k$	13.4	15.4	17.4	mA
$I_{CHV2.0}$ High Voltage Bias Current	$V_{Bias}=-32.0V; V_R=2.25V; R=2.0k$	13.3	15.3	17.3	mA
$I_{CLV0.8}$ Low Voltage Bias Current 2	$V_{Bias}=6.0V; V_R=2.45V; R=0.80k$	32.0	40.0	45.0	mA
$I_{CR32}$ Leakage Current at -32V	$V_{Bias}=-32.0V; V_R=0.00V; R=0.0k$	-100	-20	0	nA
$I_{CT+50}$ Leakage Current at +50V	$V_{Bias}=50.0V; V_R=0.00V; R=0.0k$	10	37	100	μA
$I_{CT-50}$ Leakage Current at -50V	$V_{Bias}=-50.0V; V_R=0.00V; R=0.0k$	-100	-27	1	nA
$I_{CS3.8}$ Start-up Current at 3.8V	$V_{Bias}=3.8V; V_R=0.00V; R=0.0k$	5	23	100	μA
$I_{CS32}$ Start-up Current at 32V	$V_{Bias}=-32.0V; V_R=0.00V; R=0.0k$	10	32	100	μA



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## Electrical characteristics at HOT temperature (125°C +/- 2°C) (Sample tested)

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
ID <sub>HLV2</sub> Low Voltage LED Current	V <sub>Bias</sub> =4.0V; V <sub>R</sub> =2.85V; R=2.0k	12.7	14.7	16.7	mA
ID <sub>HHV2</sub> High Voltage LED Current	V <sub>Bias</sub> =32.0V; V <sub>R</sub> =2.85V; R=2.0k	12.6	14.6	16.6	mA
ID <sub>HLV8</sub> Low Voltage LED Current	V <sub>Bias</sub> =6.0V; V <sub>R</sub> =3.10V; R=0.80k	30.0	35.9	42.0	mA
I <sub>HLV2.0</sub> Low Voltage Bias Current	V <sub>Bias</sub> =4.0V; V <sub>R</sub> =2.85V; R=2.0k	12.7	14.7	16.7	mA
I <sub>HHV2.0</sub> High Voltage Bias Current	V <sub>Bias</sub> =32.0V; V <sub>R</sub> =2.85V; R=2.0k	12.6	14.6	16.6	mA
I <sub>HLV0.8</sub> Low Voltage Bias Current	V <sub>Bias</sub> =6.0V; V <sub>R</sub> =3.10V; R=0.80k	32.0	38.5	45.0	mA
I <sub>HR32</sub> Leakage Current at -32V	V <sub>Bias</sub> =-32.0V; V <sub>R</sub> =0.00V; R=0.0k	-20	-1.5	0	µA
I <sub>HT+50</sub> Leakage Current at +50V	V <sub>Bias</sub> =50.0V; V <sub>R</sub> =0.00V; R=0.0k	10	34.0	100	µA
I <sub>HT-50</sub> Leakage Current at -50V	V <sub>Bias</sub> =-50.0V; V <sub>R</sub> =0.00V; R=0.0k	-20	-1.8	0	µA
I <sub>HS3.8</sub> Start-up Current at 3.8V	V <sub>Bias</sub> =3.8V; V <sub>R</sub> =0.00V; R=0.0k	5	19.0	100	µA
I <sub>HS32</sub> Start-up Current at 32V	V <sub>Bias</sub> =-32.0V; V <sub>R</sub> =0.00V; R=0.0k	10	28.0	100	µA

## Die dimensions

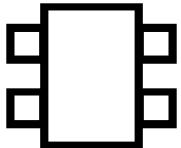
PARAMETER	MIN	TYP	MAX	UNIT
Y <sub>SIZE</sub> Long Side Dimensions	1000	1050	1100	µm
X <sub>SIZE</sub> Short Side Dimensions	765	815	865	µm
Z <sub>SIZE</sub> Die Thickness	260	285	310	µm

## Product qualification tests

PARAMETER	Lot Sampled	Sample Size	Fails Allowed	UNIT
Static burn-in 1000hrs @ V <sub>BIAS</sub> =32V; MIL STD 883 method 1015	3	22	0	n/a
Physical dimensions	3	11	0	n/a
Wire Bond Evaluation (Gold Ball Bond) per MIL STD 883 method 2011	3	20	1	n/a
COLD temperature electrical test	each	22	0	n/a
HOT temperature electrical test	each	22	0	n/a

## Visual inspection

PARAMETER	Lot Sampled	Sample Size	Fails Allowed	UNIT
100% Visual Inspection per MIL STD 883H Method 2010 Condition S.	ALL	100%	n/a	n/a



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## OPTO-COUPLER or SSR LED DRIVER

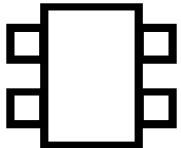
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### Lot acceptance tests

PARAMETER	Lot Sampled	Sample Size	Fails Allowed	UNIT
Static burn-in 125C; 168hrs; V <sub>BIAS</sub> =32V; V <sub>r</sub> =2.25V; R=2000 Ohm MIL STD 883 method 1015	each	22	0	n/a
Physical dimensions	each	11	0	n/a
Wire Bond Evaluation (Gold Ball Bond) per MIL STD 883 method 2011	each	20	1	n/a
COLD temperature electrical test	each	22	0	n/a
HOT temperature electrical test	each	22	0	n/a

Product qualification tests are done on 3 batches only while lot acceptance test are performed on each “diffusion lot”. Lot acceptance tests (LAT) are considered done if the lot in question was used for product qualification.

All samples used for qualification and LAT burn-in test are assembled in a open cavity ceramic DIL package with a dielectric silicone gel filling the cavity where the chip is mounted to provide isolation between the wirebonds and the substrate and to eliminate surface conduction and polarization as possible means of unwanted failure.

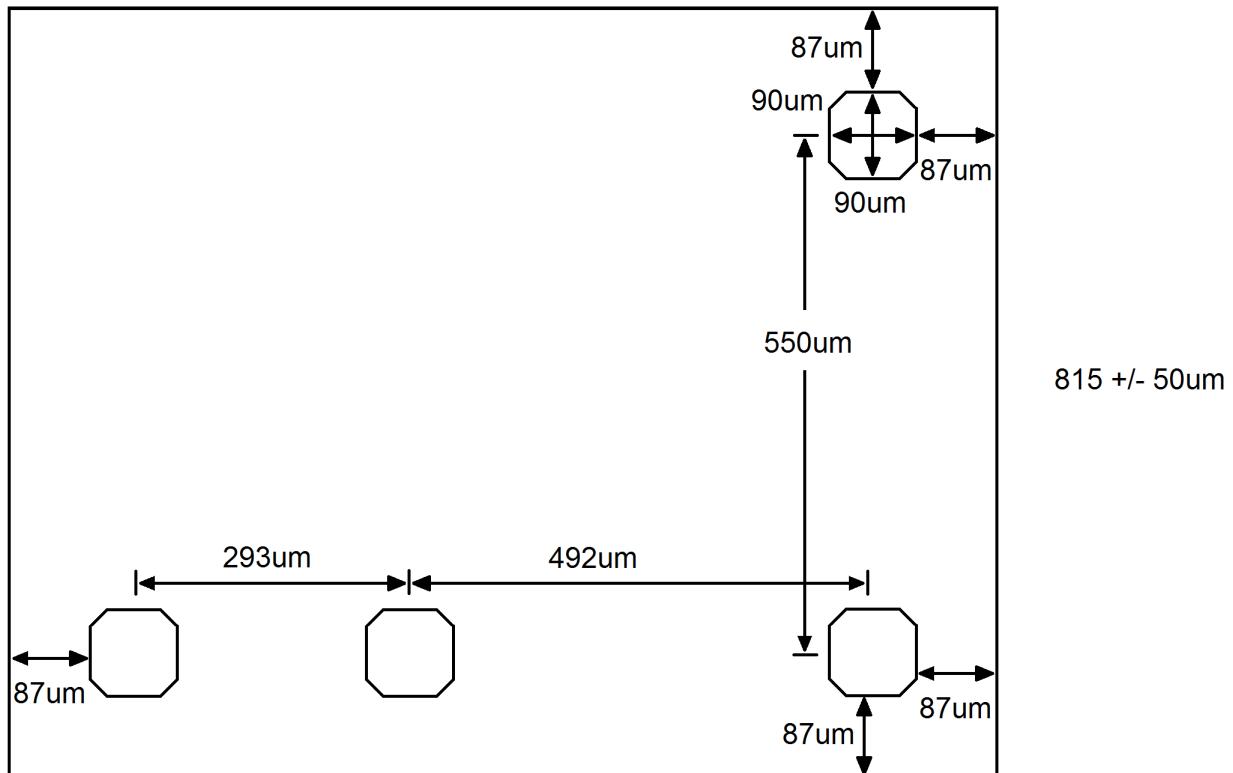


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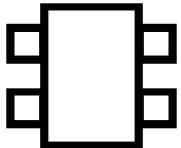
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## Die dimensions

1050 +/-50um



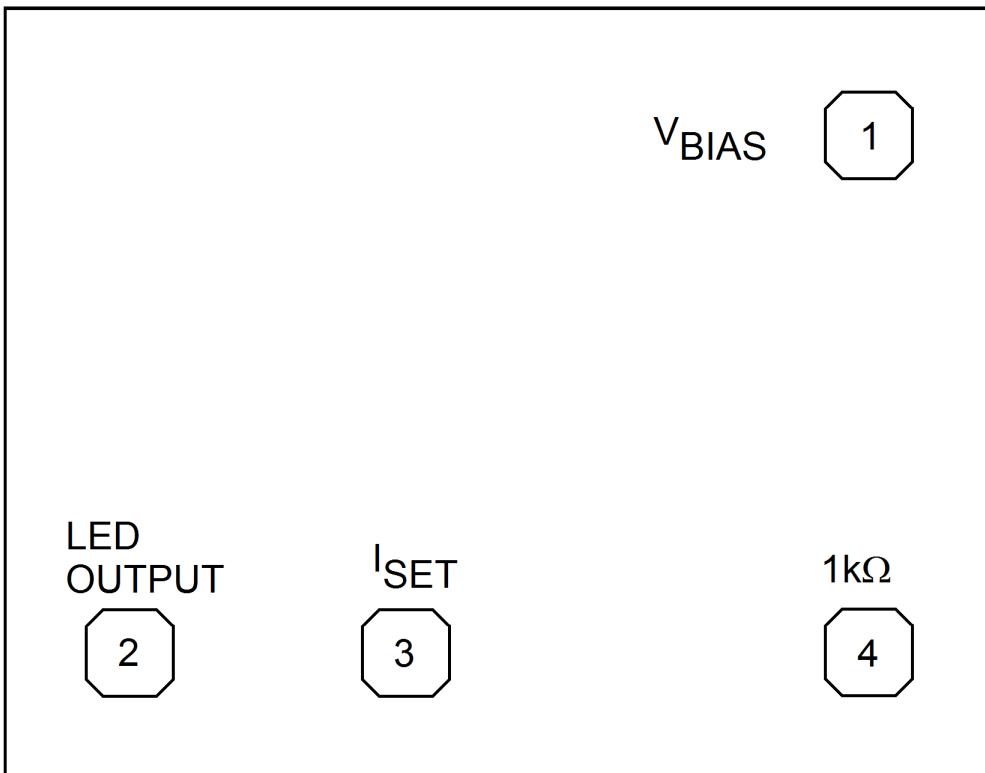
## Pin-Out

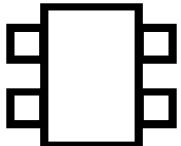


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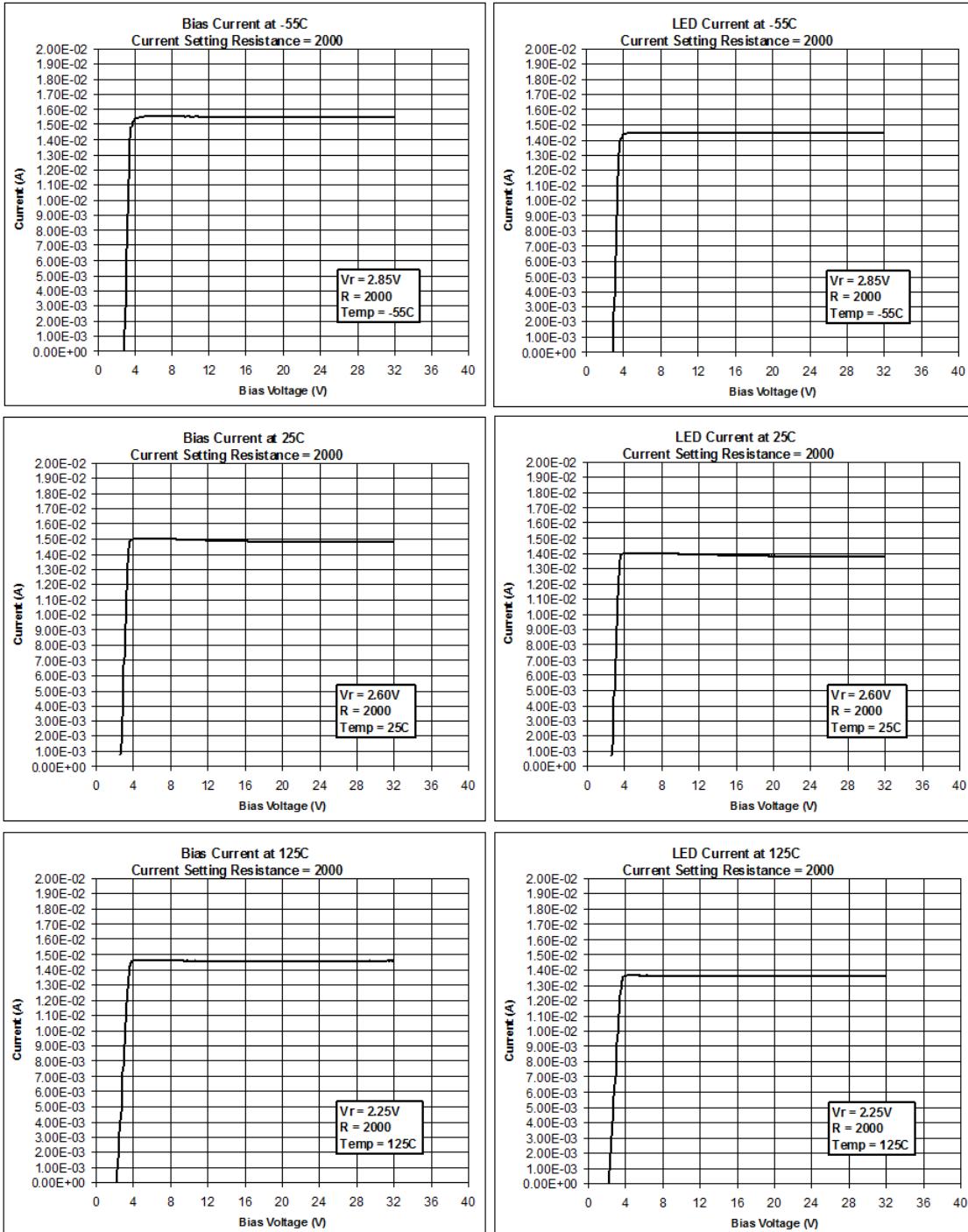


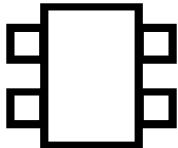


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## TYPICAL PERFORMANCE CURVES





# 14SCT001

## OPTO-COUPLER or SSR LED DRIVER

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### TYPICAL PERFORMANCE CURVES

